

XG6510B8

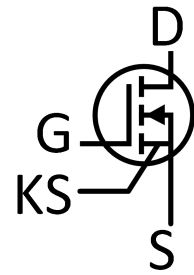
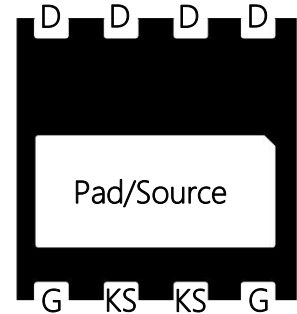
N-channel 650V 100mΩ E-Mode GaN HEMT in 8X8 DFN Package

(Datasheet Version: 2.0 Preliminary)

Features

BV_{dss}	R_{dson}	I_{ds}	Q_g
650 V	100 mΩ	12 A	3.4 nC

- Enhancement mode (E-mode)
- p-GaN with GaN-on-Si technology
- High quality packaging materials
- Easy gate-drive configurations
- High frequency switching capable
- Kelvin-source for low parasitic inductance
- Zero reverse recovery losses
- Double gate pins, connect either or both



Applications

■ PD Adapters; Quick Chargers	■ Power Factor Corrections
■ Switching Power Supplies	■ Appliance motor-drives
■ PC and server powers	■ LED drivers
■ Battery fast chargers	■ PLC, POE power

Description

- Our xGaN series devices are N-channel 650V enhancement mode (E-mode) power GaN HEMTs based on proprietary 6-inch GaN-on-silicon and p-GaN technology. Packaged with high quality materials, xGaN series devices are easy to drive, capable of switching at higher frequencies with zero reverse recovery. All xGaN devices have Kelvin-sources for reduced parasitic inductance while devices with double gate-pins and double Kelvin-source-pins (products coded with B5 and B8) offer the freedom to choose either left or right gate-pins (or connect both). This provides ultimate convenience for system designers, especially for situations where optimal PCB routing is difficult to achieve

Device Characteristics

Static Parameters				Test data			
	Parameters		Conditions	Min	Typical	Max	Unit
1	$V_{gs(TH)}$	Gate threshold voltage	$V_{ds}=V_{gs}$ $I_d=3.5mA$	0.8	1.0	1.3	V
2	BV_{dss}	Drain-Source breakdown voltage	$V_{gs}=0V$ $I_d=25\mu A$		650		V
3	I_{dss}	Zero gate voltage drain current, $T_C = 25^\circ C$	$V_{gs}=0V$ $V_{ds}=650V$		3		μA
4	I_{dss}	Zero gate voltage drain current, $T_C = 150^\circ C$	$V_{gs}=0V$ $V_{ds}=650V$		20		μA
5	I_{gss}	Gate-Source Leakage	$V_{gs} = 6V$ $V_{ds} = 0V$		300		μA
6	R_{dson}	Static drain-source on resistance, $T_C = 25^\circ C$	$V_{gs}=6V$ $I_d=5A T_j=25^\circ C$		98		m Ω
			$V_{gs}=6V$ $I_d=5A T_j=150^\circ C$		223		
7	V_{sd}	Reverse conduction voltage	$I_{sd}=1A$ $V_{gs}=0V$	1.5	1.65	2.0	V
Dynamic Parameters				Test data			
	Parameters		Conditions	Min	Typical	Max	Unit
1	C_{iss}	Input capacitance	$V_{gs}=0V$ $V_{ds}=400V$ $f=1MHz$		109		pf
	C_{oss}	Output capacitance			40		pf
	C_{rss}	Reverse transfer capacitance			0.23		pf
2	Q_g	Gate charge	$V_{ds}=400V$ $I_d=6A$ $V_{gs}=6V$		3.4		nC
	Q_{gs}	Gate to source charge			0.5		nC
	Q_{gd}	Gate to drain charge			0.9		nC
3	Q_{rr}	Reverse recovery charge			0		nC
Switching Performance				Test data			
	Parameters		Conditions	Min	Typical	Max	Unit
1	$t_{d(on)}$	Turn-on delay time	$V_{ds}=400V$ $I_d=2.5A$ $R_g=10\Omega$ $V_{gs}=6V$		2		ns
2	t_r	Rise time			13		ns
3	$t_{d(off)}$	Turn-off delay time			6		ns
4	t_f	Fall time			22		ns



Absolute Max. Ratings

	Symbols	Parameters	Value	Unit
1	V_{DS-max}	Breakdown voltage transient @ $T_{case}=25^{\circ}C$	750	V
2	V_{GS-max}	Gate to source max. transient voltage @ $T_{case}=25^{\circ}C$	-15 to +7	V
3	I_{ds-max}	Drain to source DC current @ $T_{case}=25^{\circ}C$	12	A
4	I_{ds-max}	Drain to source DC current @ $T_{case}=100^{\circ}C$	10	A
5	$dv/dt-max$	Drain to source voltage slew rate	150	V/nS
6	T_J-max	Max junction temperature	150	$^{\circ}C$
7	$T_s-storage$	Storage temperature	-55 to 150	$^{\circ}C$

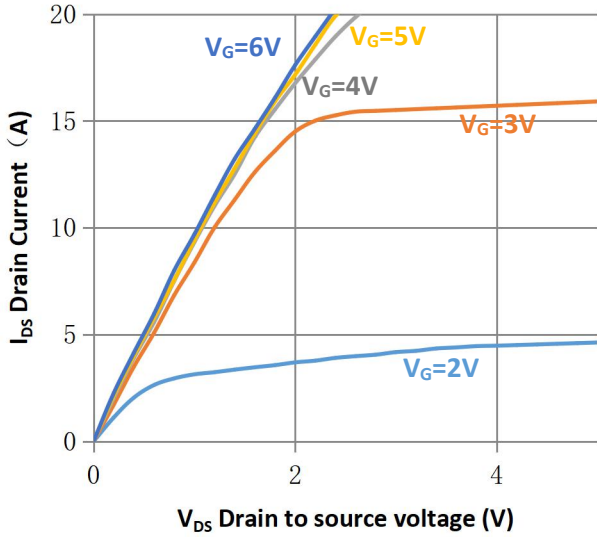
Thermal and Soldering Characteristics (Typical)

	Symbols	Parameters	Value	Unit
1	R_{thJC}	Thermal resistance (junction to case)	1.66	$^{\circ}C /W$
2	R_{thJA}	Thermal resistance (junction to ambient)	62	$^{\circ}C /W$
3	T_{solder}	Reflow soldering temperature	250	$^{\circ}C$

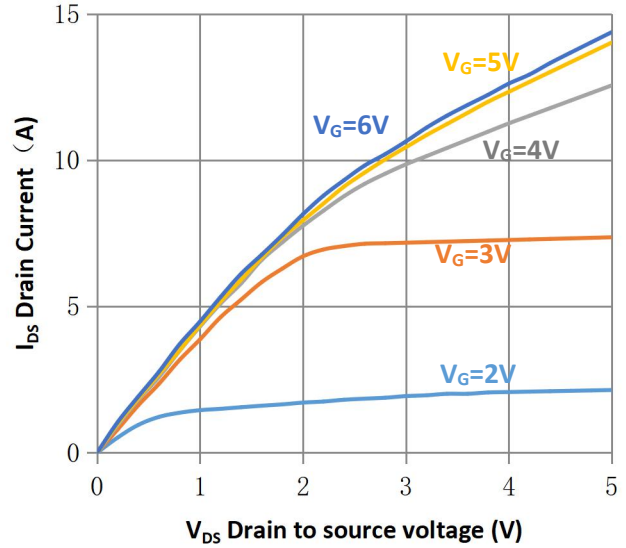
Ordering

Order Code	Package Type	Packaging Method	Qty
XG6510B8	DFN surface mount, bottom cooled, 8X8 mm	Tray	2500

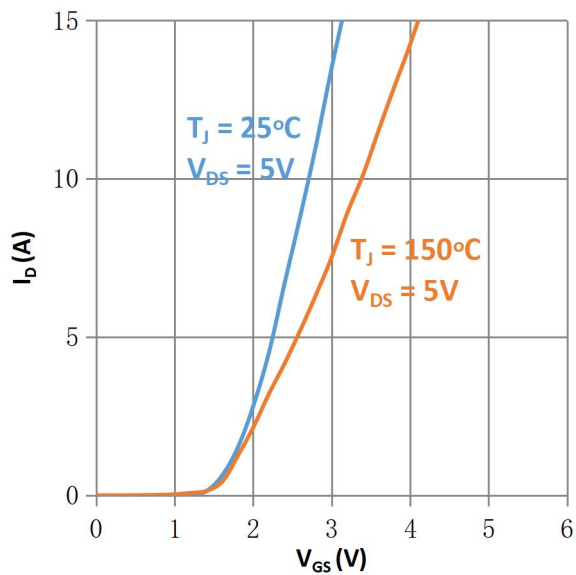
Electrical Performance



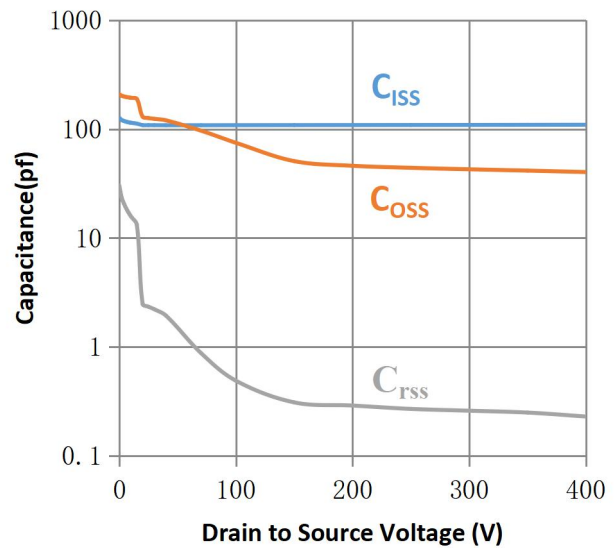
$I_{ds} - V_{ds}$ curves @25 °C



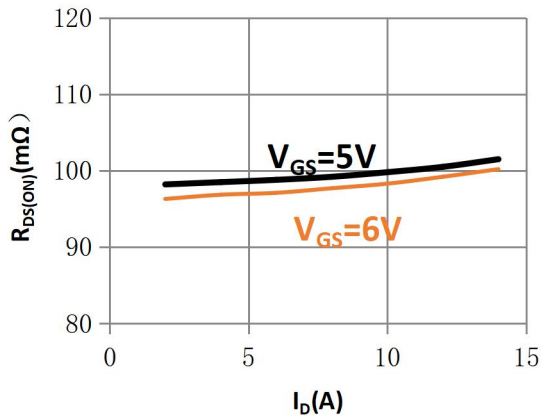
$I_{ds} - V_{ds}$ curves @150 °C



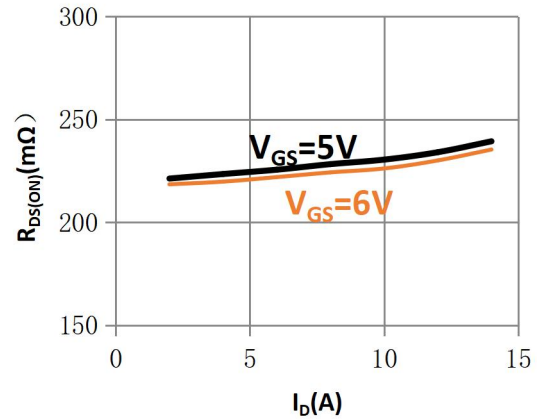
Transfer curves @25 °C & 150 °C



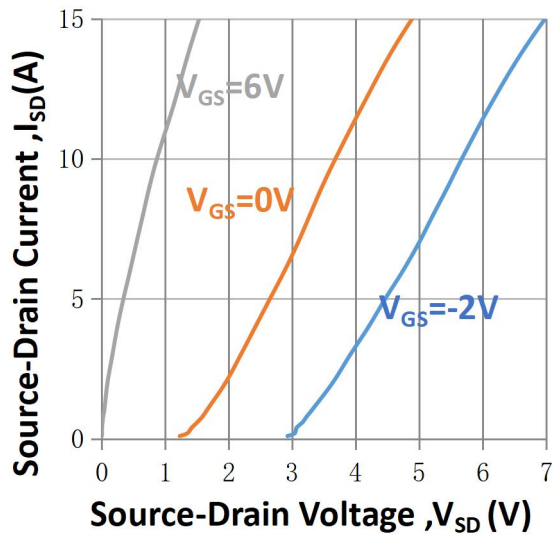
Capacitance curves



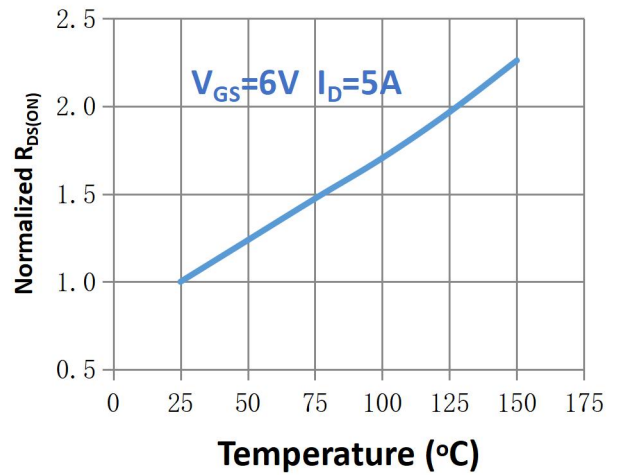
ON-resistance for various drain current @ $T_j = 25^\circ C$



ON-resistance for various drain current @ $T_j = 150^\circ C$

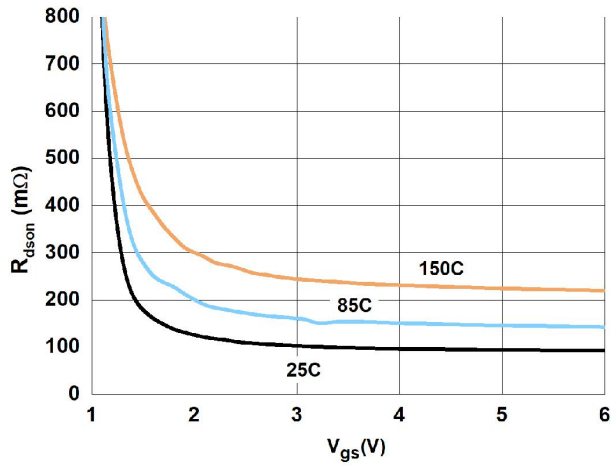


Reverse conducting curves

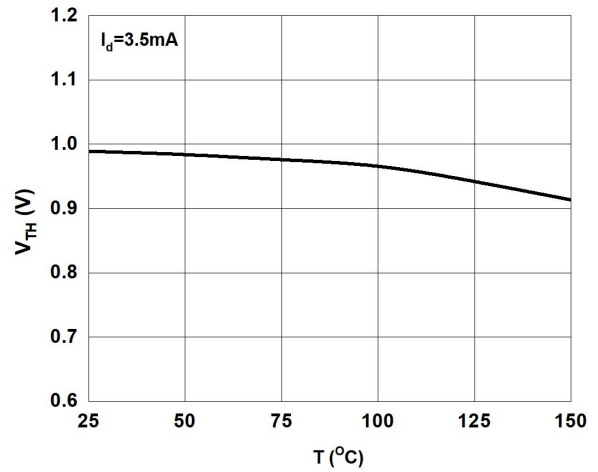


ON-resistance @ different temperatures

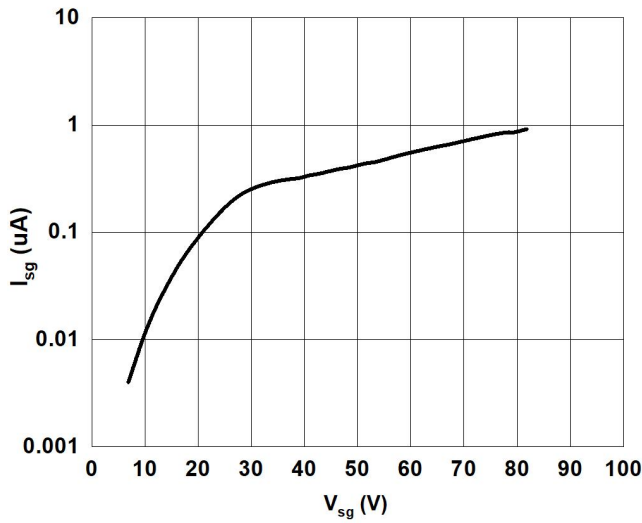




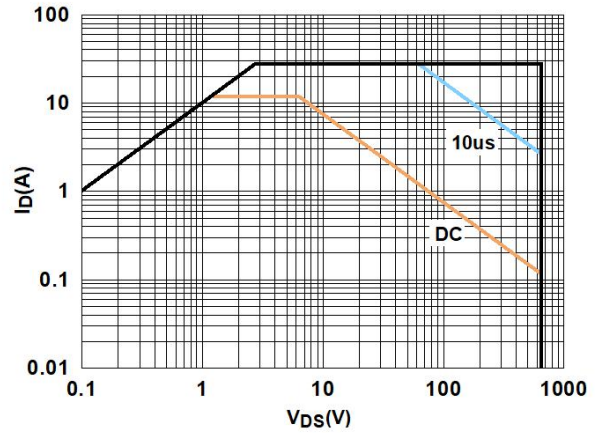
ON-resistance for @ different V_{gs}
@ $T=25^{\circ}\text{C}$ & 85°C & 150°C



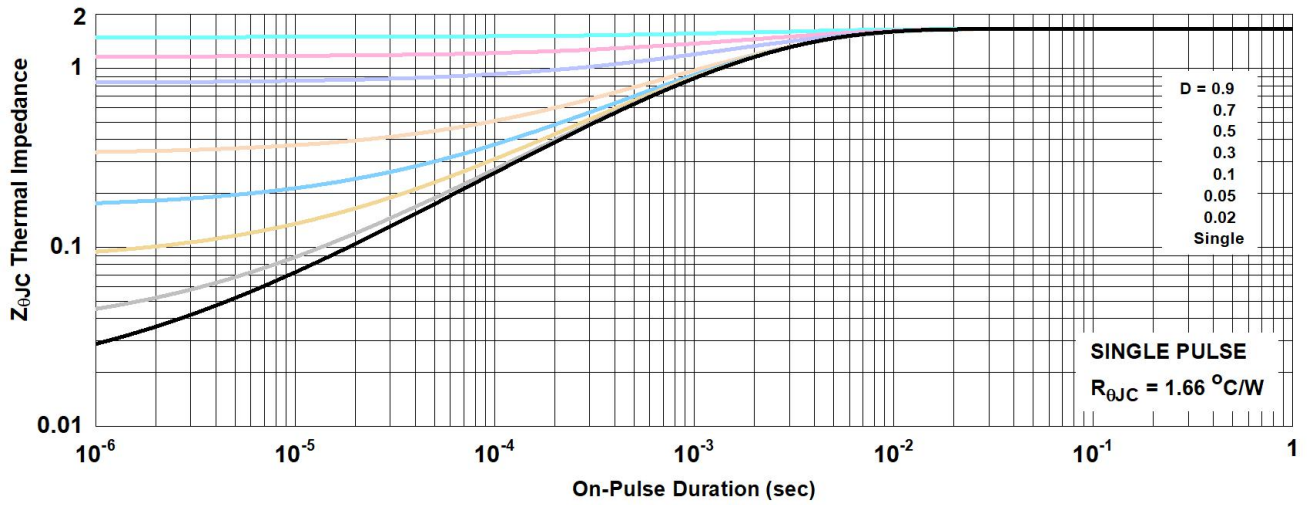
V_{th} @ different temperatures



Reverse Gate Voltage

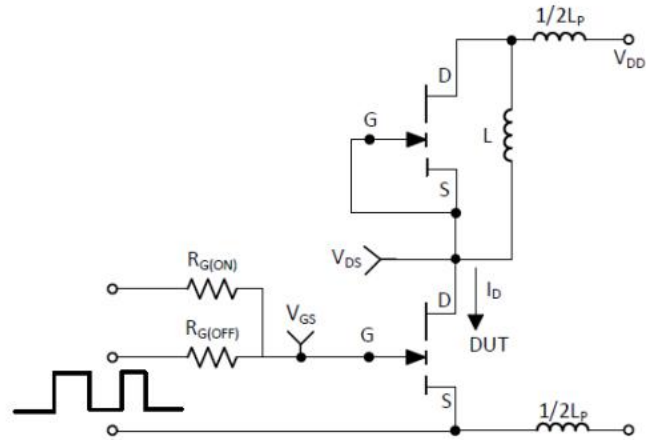


Safe Operation Area

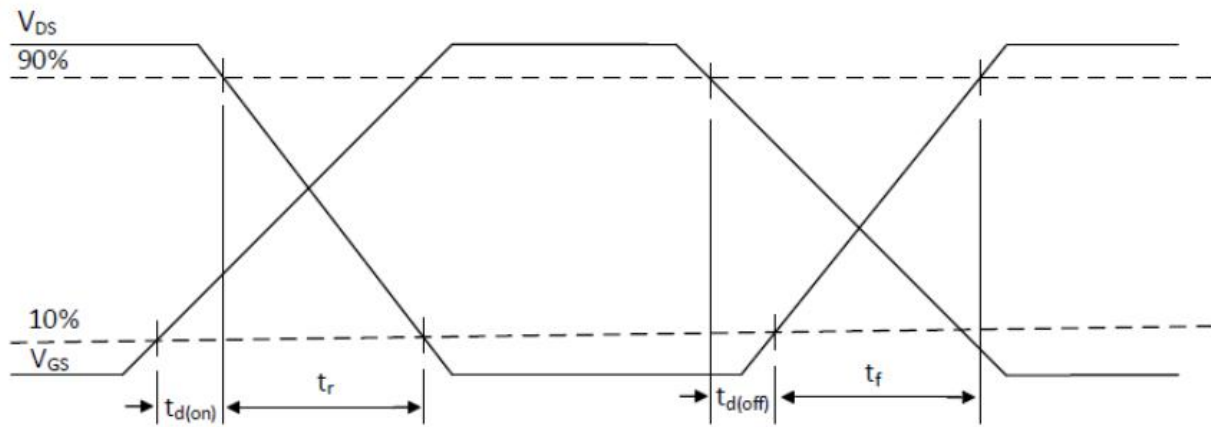


Transient Thermal Impedance





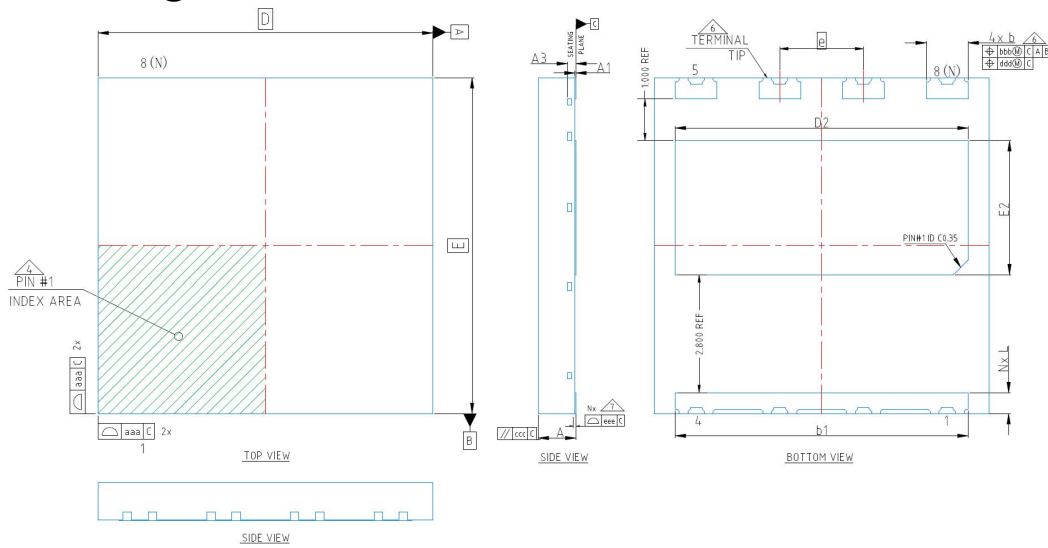
Switching Test Circuit



Switching Time Waveform



Package Information

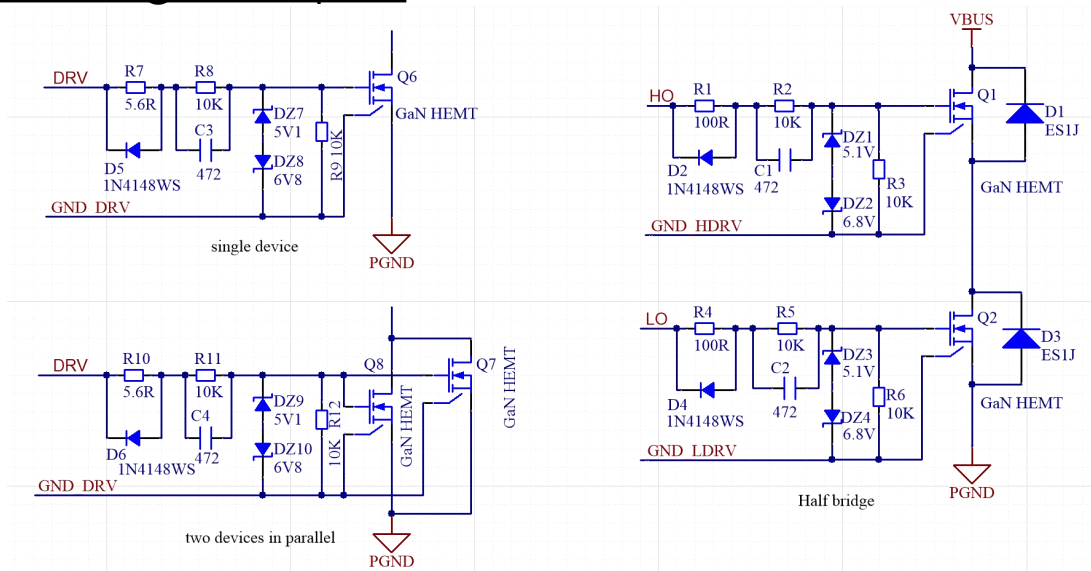


Thickness Symbol	V			W			NOTE
	MINIMUM	NOMINAL	MAXIMUM	MINIMUM	NOMINAL	MAXIMUM	
A	0.80	0.90	1.00	0.70	0.75	0.80	
A1	0.00	0.02	0.05	0.00	0.02	0.05	
A3	---	0.20 Ref	---	---	0.20 Ref	---	
b	0.90	1.00	1.10	0.90	1.00	1.10	6
b1	6.90	7.00	7.10	6.90	7.00	7.10	6
D	8.00 BSC			8.00 BSC			
E	8.00 BSC			8.00 BSC			
e	2.00 BSC			2.00 BSC			
D2	6.90	7.00	7.10	6.90	7.00	7.10	
E2	3.10	3.20	3.30	3.10	3.20	3.30	
L	0.40	0.50	0.60	0.40	0.50	0.60	
aaa	0.05						
bbb	0.10						
ccc	0.10						
ddd	0.05						
eee	0.08						
N				6			3
ND				4			5
NOTES	1, 2						
LF PART NO	446063						

NOTE:

1. Dimensioning and tolerancing conform to ASME Y14.5-2009.
2. All dimensions are in millimeters.
3. N is the total number of terminals.
4. The location of the marked terminal #1 identifier is within the hatched area.
5. ND refers to the maximum number of terminals on E side.
6. Dimension b applies to the metallized terminal. If the terminal has a radius on the other end of it, dimension b should not be measured in that radius area.
7. Coplanarity applies to the terminals and all other bottom surface metallization.

Gate Driving Examples





Gate Driving Layout Examples

